

The Seventh International Surface Cleaning Workshop Agenda

Northeastern University Campus: Raytheon Amphitheater

October 28th-29th, 2010

Thursday, October 28th, 2010

- 8:30-9:00 Registration & Breakfast - Raytheon Amphitheater**
- 9:00 - 9:10 Welcome - Ahmed Busnaina**
- Session 1, Session Chair: Jingoo Park**
- 9:10 - 9:40 Jae Hyuck Choi - Samsung
Current Status and Challenges of EUV Mask Cleaning from Industrial Perspectives
- 9:40-10:10 Mark Thirsk - Linx Consulting
Emerging Materials in Advanced Devices
- 10:10-10:40 Takeshi Hattori - Hattori Consulting International
Ultra Pure Water-Related Problems and their Solutions in Advanced Semiconductor Manufacturing
- 10:40-11:00 Break**
- Session 2, Session Chair: Rick Reidy**
- 11:00-11:30 Andreas Klipp - BASF
Development of Advanced Post Copper CMP Clean Solutions for Future Technology Nodes
- 11:30-12:00 Rakesh Singh - Entegris Inc
Post-CMP Cleaning Challenges and Opportunities
- 12:00-12:30 Shohei Shima - Ebara Corporation
Measurements of Surface Potential Non-uniformities Using KFM and EFM Techniques for Analyzing Localized Defects During CMP Process
- 12:30-2:00 LUNCH**
- Session 3, Session Chair: Joel Barnett**
- 2:00-2:30 Chung-Kyung Jung - Dongbu HiTek
A Study of Environmental Cleaning Process for Advanced Copper / low-k Device without the use of DMAC (dimethylacetamide)
- 2:30-3:00 Kevin McLaughlin - ATMI
Surface Preparation Beyond 32nm: Development of Engineered Chemistries for HKMG and Cu/ULK Applications
- 3:00-3:30 Tae-Gon Kim - IMEC
Insight of Chemical Mechanical Cleaning and Its Future
- 3:30-4:00 Break**
- Session 4, Session Chair: CK Jung**
- 4:00-4:30 Ismail Kashkoush - Akrion Systems
Wet Surface Conditioning of Monocrystalline Silicon Prior to Alkaline Texturization
- 4:30-5:00 Jin-Goo Park - Hanyang University
The Characterization and Application of Gas Dissolved DI Water to Next Generation Semiconductor Wet Process
- 5:00-7:30 Reception (406 Egan Research Center)**

Friday, October 29th, 2010

8:30-9:10 Registration & Breakfast - 440 Egan Research Center

Session 5, Session Chair: Andreas Klipp

9:10 - 9:40 Joel Barnett - Sematech

III-V materials Cleaning challenges

9:40-10:10 Michael Fury - Techcet Group

Surface Cleaning Supply Chains: Where Will the Future Come From?

10:10-10:40 Ahmed Busnaina - Northeastern University

Fundamentals of Surface Cleaning

10:40-11:00 Break

Session 6, Session Chair: Hattori

11:00-11:30 Richard Reidy - University of North Texas

The Effects of Plasma and Chemical Modification on Wetting of Low-k Films

11:30-12:00 Mark Litchy - CT Associates

Effect of Pump Pulsation and Particle Loading on Membrane Filter Particle Performance

12:00-12:30 JS Choi, IMT

Cryogenic Aerosol Cleaning

12:30-1:30 LUNCH

Session 7, Session Chair: JS Choi

1:30-2:00 Dongsik Kim - Postech University

Novel Surface Cleaning Process by Laser-induced Micro Liquid Jet

2:00-2:30 Taehoon Kim - Northeastern University

Study on Removal Mechanism of Nanoscale Particles in Wet Laser Shockwave Cleaning

2:30-3:00 Break

Session 8, Session Chair: DS Kim

3:00-3:30 Duck Joo Moon - MCK

FPD Glass Surface Preparation; Its Overview and Challenges

3:30-4:00 Jacob Andrews and Tetsu Kohyama - Entegris Inc

Advancements in Liquid Purification Technologies Using High-purity Polymer-based Membrane Filters